


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590630	<b>Applicant(s)/Patent Under Reexamination</b>  JENSEN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
reviewed search strategy for 10/590,632	11/14/2008	/YJK/
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text-search strategy	8/6/2009	/YJK/
NPL - search terms: spore, lysis, alternating electric field, bacterial/bacteria spore.	8/6/2009	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Young J Kim/ Primary Examiner.Art Unit 1637
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